

FDZ2551N

Dual N-Channel 2.5V Specified PowerTrench® BGA MOSFET

General Description

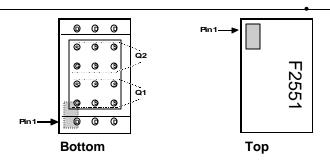
Combining Fairchild's advanced 2.5V specified PowerTrench process with state-of-the-art BGA packaging, the FDZ2551N minimizes both PCB space and $R_{DS(ON)}$. This dual BGA MDSFET embodies a breakthrough in packaging technology which enables the device to combine excellent thermal transfer characteristics, high current handling capability, ultra-low profile packaging, low gate charge, and low $R_{DS(ON)}$.

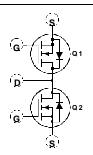
Applications

- · Battery management
- · Load switch
- · Battery protection

Features

- 9 A, 20 V. $R_{DS(ON)} = 18 \text{ m}\Omega @ V_{GS} = 4.5 \text{ V}$ $R_{DS(ON)} = 30 \text{ m}\Omega @ V_{GS} = 2.5 \text{ V}$
- Occupies only 0.10 cm² of PCB area: 1/3 the area of SO-8.
- Ultra-thin package: less than 0.70 mm height when mounted to PCB.
- Outstanding thermal transfer characteristics: significantly better than SO-8.
- Ultra-low Q_g x R_{DS(ON)} figure-of-merit
- · High power and current handling capability





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V_{DSS}	Drain-Source Voltage		20	V
V_{GSS}	Gate-Source Voltage		±12	V
I _D	Drain Current - Continuous	(Note 1a)	9	А
	- Pulsed		20	
P _D	Power Dissipation (Steady State)	(Note 1a)	2.1	W
T _J , T _{STG}	Operating and Storage Junction Tempera	ture Range	-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	60	°C/W
$R_{\theta JB}$	Thermal Resistance, Junction-to-Ball	(Note 1)	6.3	°C/W
R _{θJC}	Thermal Resistance, Junction-to-Case	(Note 1)	0.6	°C/W

Package Marking and Ordering Information

	<u> </u>			
Device Marking	Device	Reel Size	Tape width	Quantity
2551N	FDZ2551N	7"	12mm	3000 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics			I	I	ı
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	20			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		14		mV/°C
l _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 16 \text{ V}, V_{GS} = 0 \text{ V}$			1	μΑ
GSSF	Gate-Body Leakage, Forward	$V_{GS} = 12 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA
GSSR	Gate-Body Leakage, Reverse	$V_{GS} = -12 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	0.6	0.9	1.5	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		-3		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	V _{GS} = 4.5 V, I _D = 9 A V _{GS} = 2.5 V, I _D = 7 A V _{GS} = 4.5 V, I _D = 9 A, T _J =125°C		15 22 21	18 30 27	mΩ
I _{D(on)}	On–State Drain Current Forward Trans conductance	$V_{GS} = 4.5 \text{ V}, V_{DS} = 5 \text{ V}$	20			A S
Dynamic C _{iss}	Characteristics Input Capacitance	$V_{DS} = 10 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		941		pF
C _{iss}		$V_{DS} = 10 \text{ V}, \qquad V_{GS} = 0 \text{ V},$ $f = 1.0 \text{ MHz}$		941 252		pF pF
	Input Capacitance	, ,		_		<u> </u>
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	, ,		252		pF
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance	, ,		252	14	pF
C _{iss} C _{oss} C _{rss} Switching	Input Capacitance Output Capacitance Reverse Transfer Capacitance g Characteristics (Note 2)	f = 1.0 MHz		252 106	14 12	pF pF
C_{iss} C_{oss} C_{rss} $Switchin$ $t_{d(on)}$ t_{r}	Input Capacitance Output Capacitance Reverse Transfer Capacitance g Characteristics (Note 2) Turn-On Delay Time	f = 1.0 MHz $V_{DD} = 10 \text{ V}, \qquad I_D = 1 \text{ A},$		252 106		pF pF
C _{iss} C _{oss} C _{rss} Switchin	Input Capacitance Output Capacitance Reverse Transfer Capacitance g Characteristics (Note 2) Turn-On Delay Time Turn-On Rise Time	f = 1.0 MHz $V_{DD} = 10 \text{ V}, \qquad I_D = 1 \text{ A},$		252 106 7 6	12	pF pF ns
Ciss Coss Crss Switchin td(on) tr	Input Capacitance Output Capacitance Reverse Transfer Capacitance g Characteristics (Note 2) Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time	$f = 1.0 \text{ MHz}$ $V_{DD} = 10 \text{ V}, \qquad I_{D} = 1 \text{ A},$ $V_{GS} = 4.5 \text{ V}, \qquad R_{GEN} = 6 \Omega$ $V_{DS} = 10 \text{ V}, \qquad I_{D} = 9 \text{ A},$		252 106 7 6 19	12 34	pF pF pF
Ciss Coss Crss Switchin td(on) tr td(off)	Input Capacitance Output Capacitance Reverse Transfer Capacitance g Characteristics (Note 2) Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time	$f=1.0 \text{ MHz}$ $V_{DD}=10 \text{ V}, \qquad I_{D}=1 \text{ A},$ $V_{GS}=4.5 \text{ V}, \qquad R_{GEN}=6 \Omega$		252 106 7 6 19 10	12 34 20	pF pF ns ns
Ciss Coss Crss Switchin td(on) tr td(off) tf	Input Capacitance Output Capacitance Reverse Transfer Capacitance g Characteristics (Note 2) Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge	$f = 1.0 \text{ MHz}$ $V_{DD} = 10 \text{ V}, \qquad I_{D} = 1 \text{ A},$ $V_{GS} = 4.5 \text{ V}, \qquad R_{GEN} = 6 \Omega$ $V_{DS} = 10 \text{ V}, \qquad I_{D} = 9 \text{ A},$		252 106 7 6 19 10 9.6	12 34 20	pF pF ns ns ns ns
Ciss Coss Crss Switchin t _{d(on)} tr t _{d(off)} t _t Q _g Q _{gs} Q _{gd}	Input Capacitance Output Capacitance Reverse Transfer Capacitance g Characteristics (Note 2) Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge	$\begin{split} f &= 1.0 \text{ MHz} \\ \\ V_{DD} &= 10 \text{ V}, & I_D &= 1 \text{ A}, \\ V_{GS} &= 4.5 \text{ V}, & R_{GEN} &= 6 \Omega \\ \\ \\ V_{DS} &= 10 \text{ V}, & I_D &= 9 \text{ A}, \\ V_{GS} &= 4.5 \text{ V} \end{split}$		252 106 7 6 19 10 9.6 2	12 34 20	pF pF ns ns ns ns nc nC
Ciss Coss Crss Switchin t _{d(on)} tr t _{d(off)} t _t Q _g Q _{gs} Q _{gd}	Input Capacitance Output Capacitance Reverse Transfer Capacitance g Characteristics (Note 2) Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge	$f=1.0 \text{ MHz}$ $V_{DD}=10 \text{ V}, \qquad I_{D}=1 \text{ A},$ $V_{GS}=4.5 \text{ V}, \qquad R_{GEN}=6 \Omega$ $V_{DS}=10 \text{ V}, \qquad I_{D}=9 \text{ A},$ $V_{GS}=4.5 \text{ V}$ and Maximum Ratings		252 106 7 6 19 10 9.6 2	12 34 20	pF pF ns ns ns ns nc nC

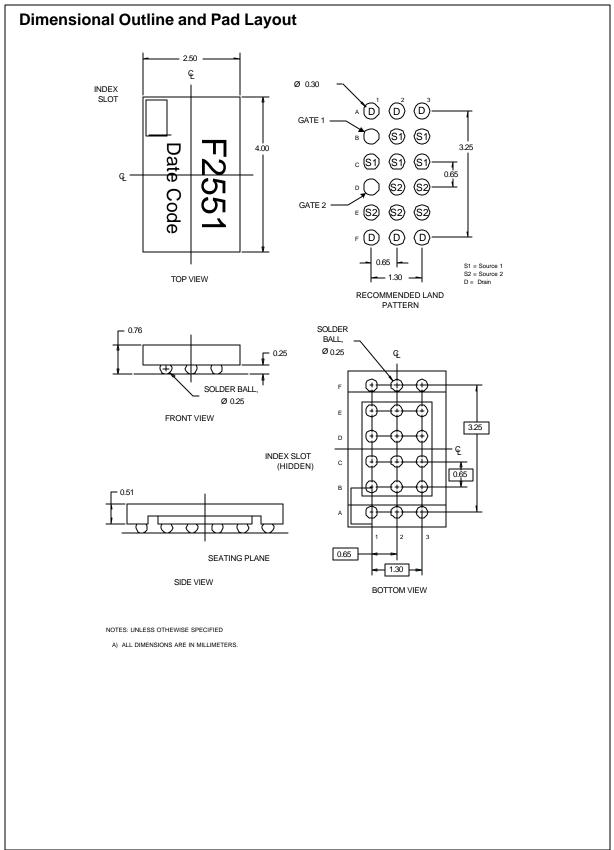
Notes:

(a). R $_{\theta JA} = 60^{\circ} \text{C/W}$ when mounted on a 1ir² pad of 2 oz copper, 1.5" x 1.5" x 0.062" thick PCB

^{1.} R_{0,JA} is determined with the device mounted on a 1 in² 2 oz. copper pad on a 1.5 x 1.5 in. board of FR-4 material. The thermal resistance from the junction to the circuit board side of the solder ball, R_{0,JB} is defined for reference. For R_{0,C}, the thermal reference point for the case is defined as the top surface of the copper chip carrier. R_{0,C} and R_{0,JB} are guaranteed by design while R_{0,JA} is determined by the user's board design.

⁽b). $R_{\theta JA} = 108^{\circ} C/W$ when mounted on a minimum pad of 2 oz copper

^{2.} Pulse Test: Pulse Width < 300μ s, Duty Cycle < 2.0%



Typical Characteristics

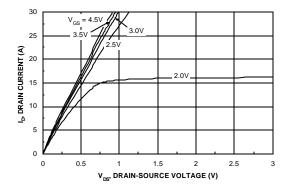


Figure 1. On-Region Characteristics.

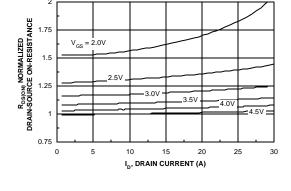


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

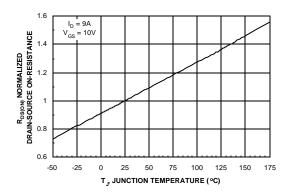


Figure 3. On-Resistance Variation with Temperature.

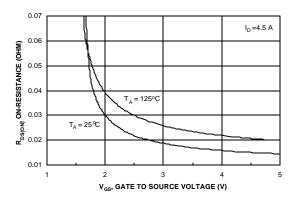


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

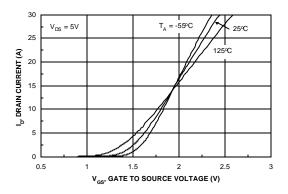


Figure 5. Transfer Characteristics.

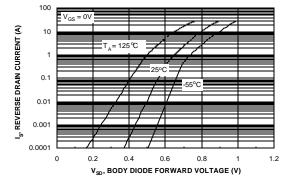
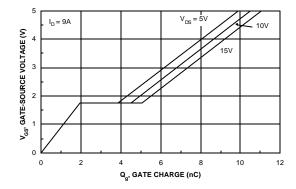


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



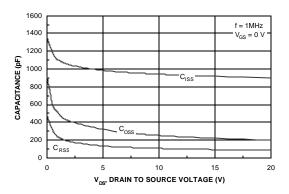
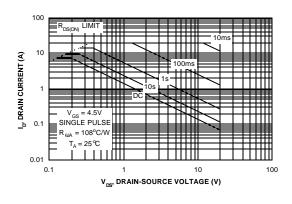


Figure 7. Gate Charge Characteristics.





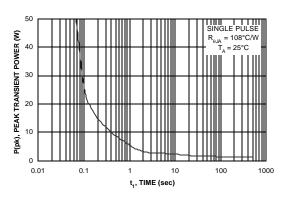


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

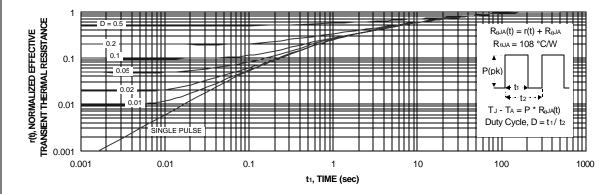


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

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